



From the Editor

Elements in Microscopy and Microanalysis

The Microscopy Society of America (MSA) and Cambridge University Press (CUP) are again collaborating to add a new publication to their portfolio: *Elements of Microscopy and Microanalysis*. Cambridge “*Elements*” are a new concept in academic publishing and scholarly communication, combining the best features of books and journals. They consist of original, concise, authoritative, and peer-reviewed scholarly research and educational material of approximately 70 to 90 pages that are organized into a focused series edited by leading scholars. Conceived for the digital environment, “*Elements*” are published primarily online but are also available as a print-on-demand publication. As a primarily digital publication, each “*Element*” will be dynamic, with opportunities for the authors to provide annual updates as new technology and applications become available. Moreover, “*Elements*” supports embedded multimedia components such as video and code.

Elements in Microscopy and Microanalysis will complement MSA’s peer-reviewed journal, *Microscopy and Microanalysis*, and magazine, *Microscopy Today*, by rapidly publishing manuscripts that are too long for these traditional publications. Entries in the series will represent the wide range of microscopy and microanalysis content found in MSA publications as well as the annual *Microscopy & Microanalysis* meeting, including advances in instrumentation, technique development, data analysis, and applications in the biological and materials sciences. Content will consist of tutorial presentations of state-of-the-art research, in addition to relevant advances in techniques related to rapidly evolving fields such as cryo-electron and super-resolution microscopy. As noted above, each “*Element*” will be a dynamic publication making it possible for the author to update the publication with new results and techniques annually.

The founding Editor-in-Chief of *Elements of Microscopy and Microanalysis*, Dr. Beth Dickey of North Carolina State University, has established an editorial board of international experts in microscopy and microanalysis: Drs. Lena Kourkoutis of Cornell University, Teng-Leong Chew of the HHMI Janelia Research Campus, Marc De Graef of Carnegie Mellon University, Susan Hafenstein of The Pennsylvania State University, and Eric Stach of the University of Pennsylvania. For further information please contact Beth or a member of the Editorial Board if you would like to submit an “*Element*” for publication.

Robert L. Price
Editor-in-Chief

Publication Objective: to provide information of interest to microscopists.

Microscopy Today is a controlled-circulation trade magazine owned by the Microscopy Society of America that is published six times a year in the odd months. Editorial coverage spans all microscopy techniques including light microscopy, scanning probe microscopy, electron microscopy, ion-beam techniques, and the wide range of microanalytical methods. Readers and authors come from both the life sciences and the physical sciences. The typical length of an article is about 2,000 words plus figures and tables; feature articles are longer. Interested authors should consult “Instructions for Contributors” on the *Microscopy Today* website: www.microscopy-today.com.

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